

AON2801
Dual P-Channel Enhancement Mode Field Effect Transistor
General Description

The AON2801/L uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications.

AON2801 and AON2801L are electrically identical.

-RoHS Compliant

-AON2801L is Halogen Free

Features

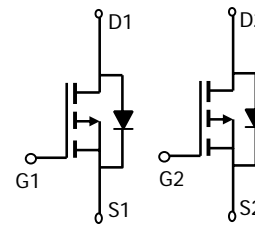
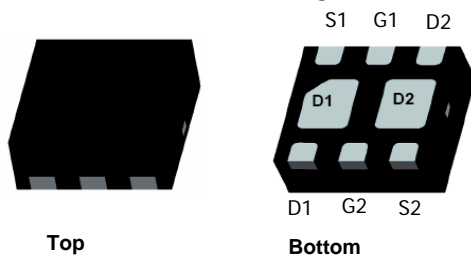
$$V_{DS} (V) = -20V$$

$$I_D = -3A \quad (V_{GS} = -4.5V)$$

$$R_{DS(ON)} < 120m\Omega \quad (V_{GS} = -4.5V)$$

$$R_{DS(ON)} < 160m\Omega \quad (V_{GS} = -2.5V)$$

$$R_{DS(ON)} < 200m\Omega \quad (V_{GS} = -1.8V)$$

DFN 2x2 Package


Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 8	V
Continuous Drain Current ^A	I_D	$T_A=25^\circ C$	-3
		$T_A=70^\circ C$	-2.3
Pulsed Drain Current ^C	I_{DM}	-15	A
Power Dissipation ^A	P_{DSM}	$T_A=25^\circ C$	1.5
		$T_A=70^\circ C$	0.95
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	$t \leq 10s$	35	$^\circ C/W$
Maximum Junction-to-Ambient ^A		Steady-State	65	$^\circ C/W$
Maximum Junction-to-Ambient ^B	$R_{\theta JA}$	$t \leq 10s$	120	$^\circ C/W$
Maximum Junction-to-Ambient ^B		Steady-State	175	$^\circ C/W$

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}$, $V_{GS}=0\text{V}$	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-20\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 8\text{V}$			± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=-250\mu\text{A}$	-0.3	-0.55	-1	V
$I_{D(ON)}$	On state drain current	$V_{GS}=-4.5\text{V}$, $V_{DS}=-5\text{V}$	-15			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}$, $I_D=-3\text{A}$ $T_J=125^\circ\text{C}$		100	120	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}$, $I_D=-2.6\text{A}$		128	160	$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}$, $I_D=-1.5\text{A}$		160	200	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}$, $I_D=-3\text{A}$		6		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}$, $V_{GS}=0\text{V}$		-0.76		V
I_S	Maximum Body-Diode Continuous Current				-1	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance			540	700	pF
C_{oss}	Output Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=-10\text{V}$, $f=1\text{MHz}$		90		pF
C_{riss}	Reverse Transfer Capacitance			63		pF
R_g	Gate resistance	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$		9.5		Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge			5	6.5	nC
Q_{gs}	Gate Source Charge	$V_{GS}=-4.5\text{V}$, $V_{DS}=-10\text{V}$, $I_D=-3\text{A}$		1.2		nC
Q_{gd}	Gate Drain Charge			1		nC
$t_{D(on)}$	Turn-On Delay Time			5		ns
t_r	Turn-On Rise Time	$V_{GS}=-4.5\text{V}$, $V_{DS}=-10\text{V}$, $R_L=1.5\Omega$, $R_{GEN}=3\Omega$		40		ns
$t_{D(off)}$	Turn-Off Delay Time			28.5		ns
t_f	Turn-Off Fall Time			46		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-3\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		21	28	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-3\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		9.1		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\theta JA}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 150°C may be used if the PCB allows it to.

B: The value of $R_{\theta JA}$ is measured with the device mounted on a minimum pad board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\theta JA}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 150°C may be used if the PCB allows it to.

C: The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

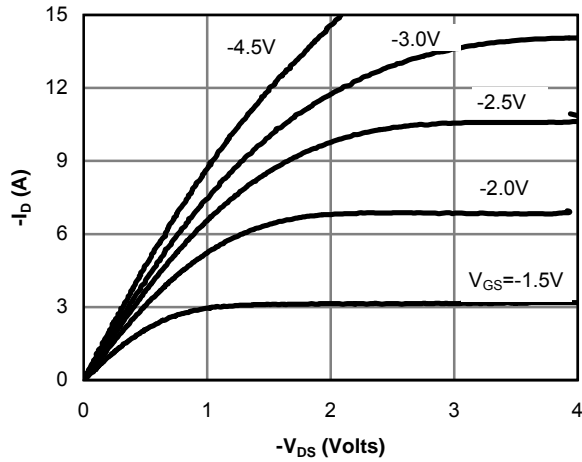


Figure 1: On-Region Characteristics

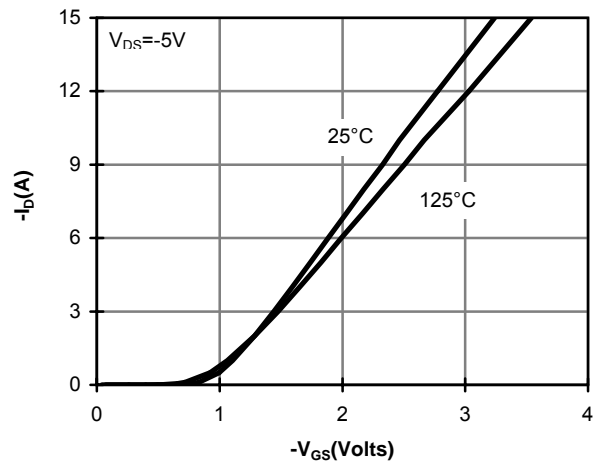


Figure 2: Transfer Characteristics

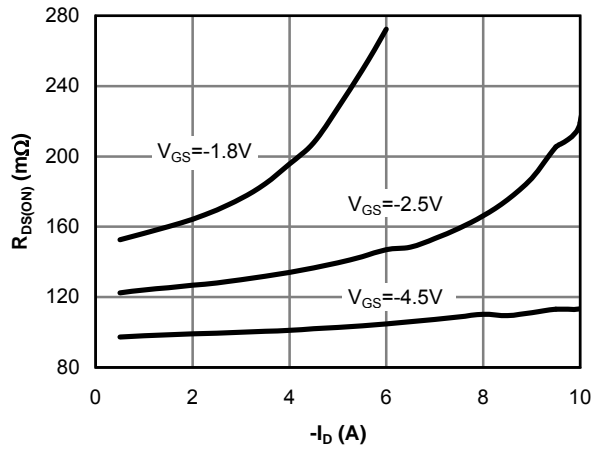


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

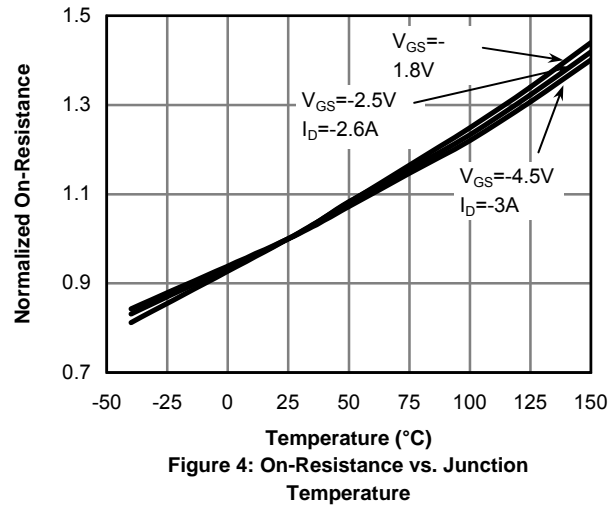


Figure 4: On-Resistance vs. Junction Temperature

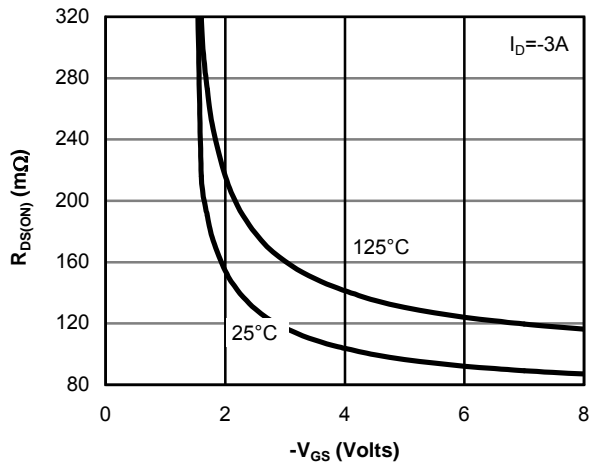


Figure 5: On-Resistance vs. Gate-Source Voltage

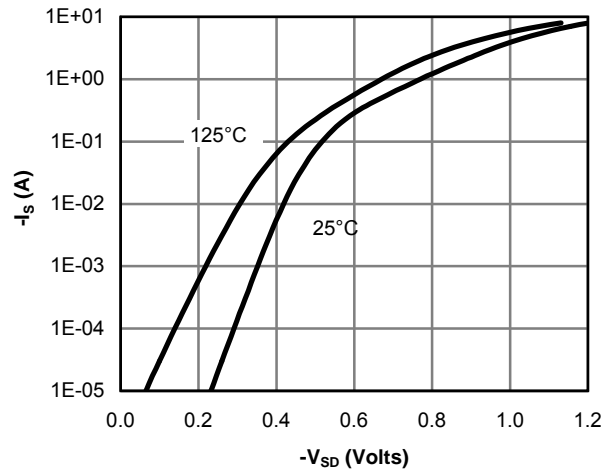


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

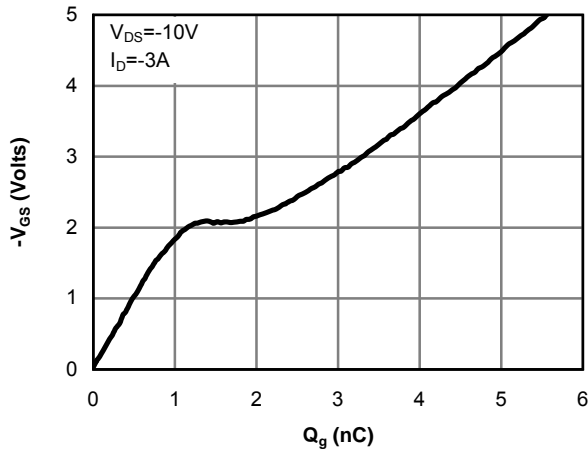


Figure 7: Gate-Charge Characteristics

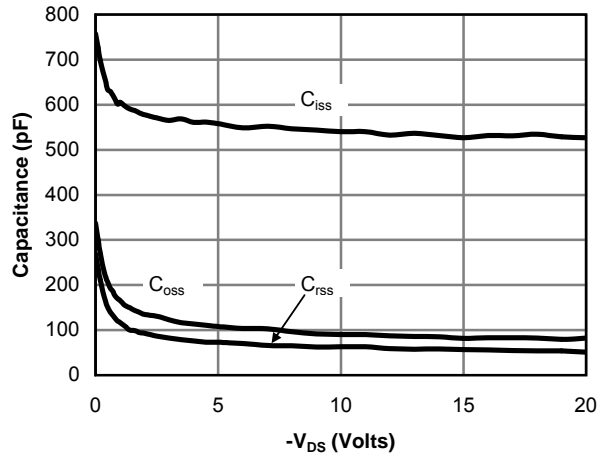


Figure 8: Capacitance Characteristics

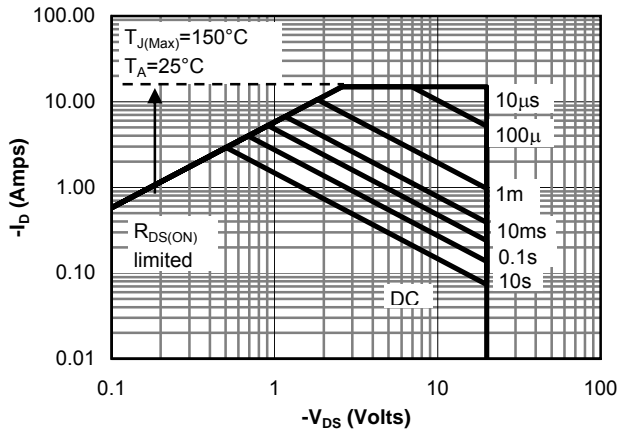


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

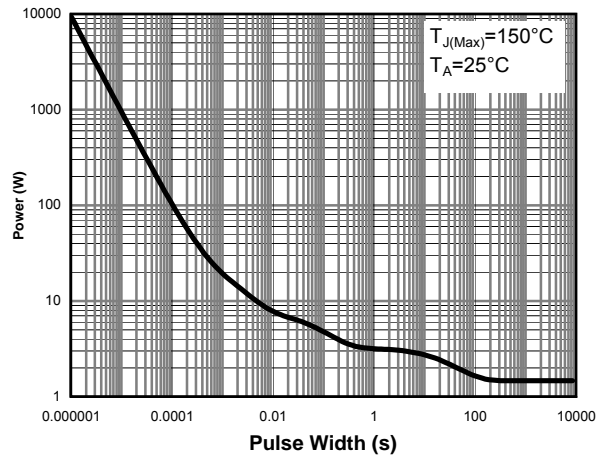


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

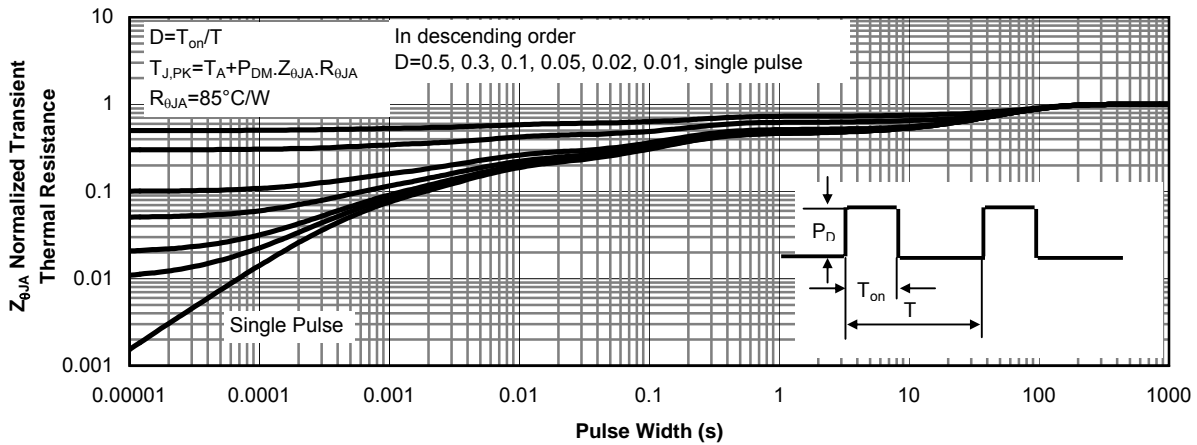


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)